

# STF20NK50Z, STP20NK50Z

# N-channel 500 V, 0.23 Ω 17 A SuperMESH™ Power MOSFET Zener-protected in TO-220FP and TO-220 packages

Datasheet — production data

#### **Features**

Order codes	V <sub>DSS</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>	P <sub>TOT</sub>
STF20NK50Z	500 V	< 0.27 Ω	17 A	40 W
STP20NK50Z	500 V	< 0.27 Ω	17 A	190 W

- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitance



■ Switching applications

#### **Description**

These devices are N-channel Zener-protected Power MOSFETs developed using STMicroelectronics' SuperMESH™ technology, achieved through optimization of ST's well established strip-based PowerMESH™ layout. In addition to a significant reduction in onresistance, this device is designed to ensure a high level of dv/dt capability for the most demanding applications.

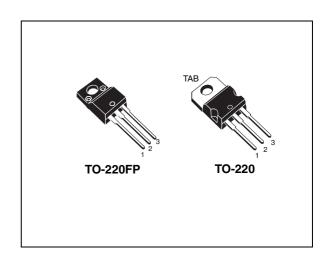


Figure 1. Internal schematic diagram

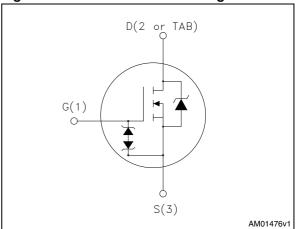


Table 1. Device summary

Order codes	Marking	Package	Packaging
STF20NK50Z	F20NK50Z	TO-220FP	Tube
STP20NK50Z	P20NK50Z	TO-220	Tube

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## 1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	9	Unit
Symbol	Parameter	TO-220	TO-220FP	Unit
V <sub>DS</sub>	Drain-source voltage	500		V
V <sub>GS</sub>	Gate-source voltage	± 30	)	V
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 25 °C	17	17 <sup>(1)</sup>	Α
I <sub>D</sub>	I <sub>D</sub> Drain current (continuous) at T <sub>C</sub> = 100 °C 10.71 1		10.71 <sup>(1)</sup>	Α
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed) 68		68	Α
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> = 25 °C	190	40	W
	Derating factor	1.52	0.32	W/°C
V <sub>ISO</sub>	$V_{ISO}$ Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; $T_C$ = 25 °C)		2500	V
ESD	Gate-source human body model (R=1.5 kΩ C=100 pF)	6		kV
dv/dt (3)	Peak diode recovery voltage slope	4.5		V/ns
T <sub>stg</sub>	Storage temperature	-55 to 150		°C
T <sub>j</sub>	Max operating junction temperature	150		°C

- 1. Limited by maximum junction temperature.
- 2. Pulse width limited by safe operating area.
- $3. \quad I_{SD} \quad \leq 17 \text{ A, di/dt} \quad \leq \ 200 \text{ A/}\mu\text{s, V}_{DD} \quad \leq \ V_{\left(BR\right)DSS}, \, T_{j} \quad \leq T_{JMAX}.$

Table 3. Thermal data

Symbol	Parameter	Value	Unit		
Symbol	raiametei	TO-220	TO-220FP	Oill	
R <sub>thj-case</sub>	Thermal resistance junction-case max	0.66	3.1	°C/W	
R <sub>thj-amb</sub>	Thermal resistance junction-ambient max	62.5	62.5	°C/W	

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not- repetitive (pulse width limited by Tj max)	17	Α
E <sub>AS</sub> Single pulse avalanche energy (starting T <sub>J</sub> =25 °C, I <sub>D</sub> =I <sub>AR</sub> , V <sub>DD</sub> =50 V)		850	mJ

### 2 Electrical characteristics

(T<sub>CASE</sub> = 25 °C unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	I <sub>D</sub> =1 mA, V <sub>GS</sub> = 0	500			V
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = 500 V V <sub>DS</sub> = 500 V, T <sub>C</sub> = 125 °C			1 50	μ <b>Α</b> μ <b>Α</b>
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20 V			± 10	μΑ
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 100 \mu A$	3	3.75	4.5	V
R <sub>DS(on)</sub>	Static drain-source on-resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 8.5 A		0.23	0.27	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0$	-	2600 328 72		pF pF pF
C <sub>oss eq.</sub> (1)	Equivalent output capacitance	$V_{DS} = 0$ , $V_{DS} = 0$ to 640 V	-	187		pF
$\begin{array}{c} t_{\text{d(on)}} \\ t_{\text{r}} \\ t_{\text{d(off)}} \\ t_{\text{f}} \end{array}$	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 250 \text{ V}, I_{D} = 8.5 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 16</i> )	-	28 20 70 15		ns ns ns ns
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	$V_{DD}$ = 400 V, $I_{D}$ = 17 A, $V_{GS}$ = 10 V (see <i>Figure 17</i> )	-	85 15.5 42	119	nC nC nC

<sup>1.</sup>  $C_{oss\ eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current Source-drain current (pulsed)		-		17 68	A A
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 17 A, V <sub>GS</sub> = 0	-		1.6	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD}$ = 17 A, di/dt = 100 A/µs $V_{R}$ = 100 V (see <i>Figure 18</i> )	-	355 3.90 22		ns μC Α
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD}$ = 17 A, di/dt = 100 A/µs $V_{R}$ = 100 V, Tj = 150 °C (see <i>Figure 18</i> )	-	440 5.72 26		ns μC A

- 1. Pulsed: pulse duration=300µs, duty cycle 1.5%
- 2. Pulse width limited by safe operating area

Table 8. Gate-source Zener diode

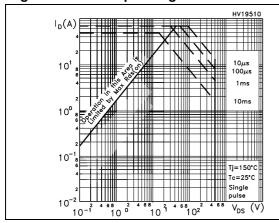
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
BV <sub>GSO</sub>	Gate-source breakdown voltage	Igs=± 1mA (open drain)	30	-		٧

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

#### 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220

Figure 3. Thermal impedance for TO-220



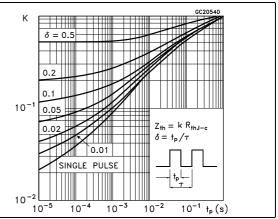
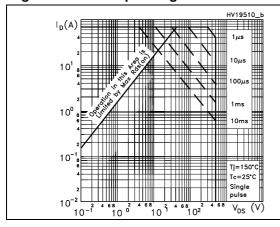


Figure 4. Safe operating area for TO-220FP

Figure 5. Thermal impedance for TO-220FP



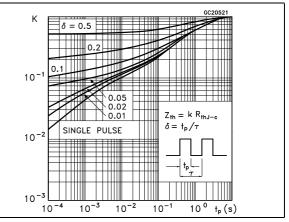
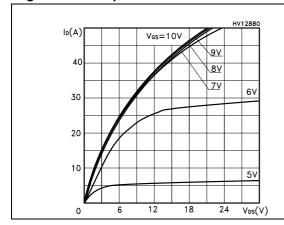


Figure 6. Output characteristics

Figure 7. Transfer characteristics



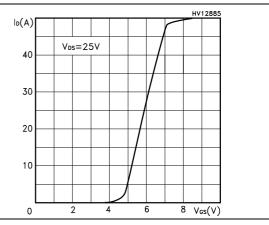
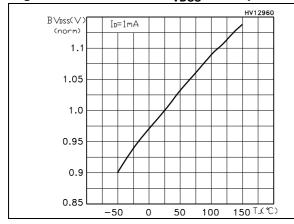


Figure 8. Normalized  $B_{VDSS}$  vs temperature Figure 9. Static drain-source on-resistance



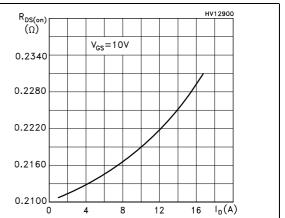
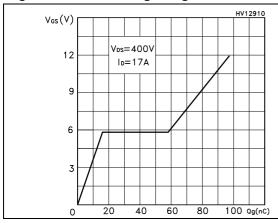


Figure 10. Gate charge vs gate-source voltage Figure 11. Capacitance variations



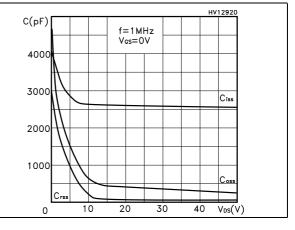
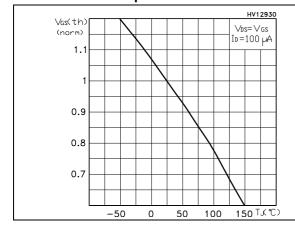


Figure 12. Normalized gate threshold voltage Figure 13. Normalized on-resistance vs vs temperature temperature



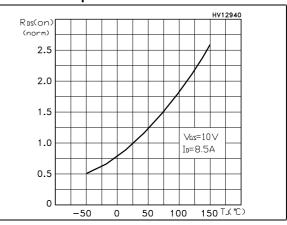


Figure 14. Maximum avalanche energy vs temperature

50

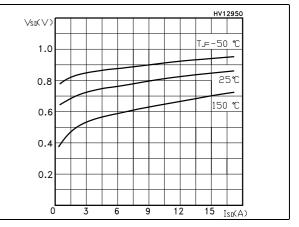
75

100

125 T√℃)

25

Figure 15. Source-drain diode forward characteristic



#### 3 Test circuits

Figure 16. Switching times test circuit for resistive load

Figure 17. Gate charge test circuit

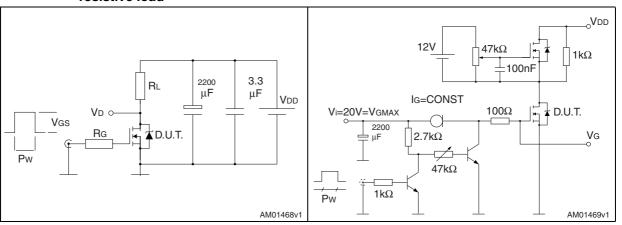


Figure 18. Test circuit for inductive load switching and diode recovery times

Figure 19. Unclamped inductive load test circuit

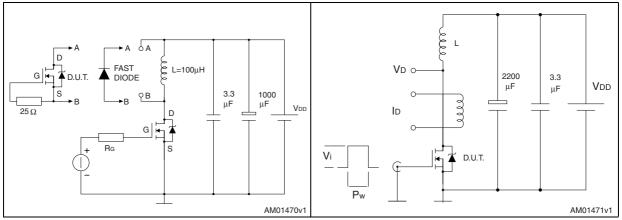
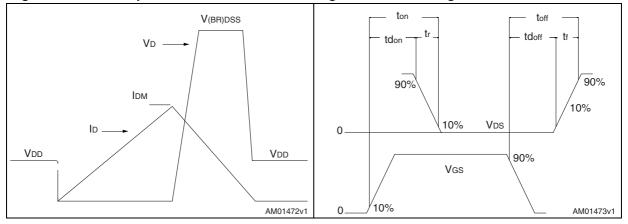


Figure 20. Unclamped inductive waveform

Figure 21. Switching time waveform



## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Table 9. TO-220FP mechanical data

D:	mm				
Dim.	Min.	Тур.	Max.		
Α	4.4		4.6		
В	2.5		2.7		
D	2.5		2.75		
E	0.45		0.7		
F	0.75		1		
F1	1.15		1.70		
F2	1.15		1.70		
G	4.95		5.2		
G1	2.4		2.7		
Н	10		10.4		
L2		16			
L3	28.6		30.6		
L4	9.8		10.6		
L5	2.9		3.6		
L6	15.9		16.4		
L7	9		9.3		
Dia	3		3.2		

*\_B*⊸ Dia *L6* L2 *L7* L3 F1 **L4** F2 -*E* 

Figure 22. TO-220FP drawing

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Table 10. TO-220 type A mechanical data

Dim		mm	
Dim.	Min.	Тур.	Max.
Α	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
С	0.48		0.70
D	15.25		15.75
D1		1.27	
Е	10		10.40
е	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
ØP	3.75		3.85
Q	2.65		2.95

Figure 23. TO-220 type A drawing

# 5 Revision history

Table 11. Document revision history

Date	Revision	Changes
05-Apr-2012	1	First release.

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